## Notice of References Cited Application/Control No. 10/541,447 Examiner Sonny TRINH Applicant(s)/Patent Under Reexamination TAN ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	А	US-2008/0219230	09-2008	Lee et al.	370/338
*	В	US-2007/0274266	11-2007	Oyama et al.	370/335
*	С	US-2005/0181764	08-2005	Hahn et al.	455/411
*	D	US-2006/0104262	05-2006	Kant et al.	370/352
*	Е	US-7,272,397	09-2007	Gallagher et al.	455/436
*	F	US-7,283,822	10-2007	Gallagher et al.	455/436
*	G	US-2008/0130637	06-2008	Kant et al.	370/389
*	Н	US-7,155,526	12-2006	Chaudhary et al.	709/229
*	I	US-7,373,661	05-2008	Smith et al.	726/15
*	J	US-7,489,659	02-2009	Siorpaes et al.	370/331
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.